

	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/717,381	MAHISHI ET AL.
ſ	Examiner	Art Unit
	Yong D. Pak	1652

SEARCHED					
Class	Subclass	Date	Examiner		
435	189	10/24/2005	YP		
435	194	10/24/2005	YP		
435	195	10/24/2005	YP		
435	252.3	10/24/2005	YP		
435	320.1	10/24/2005	YP		
435	69.1	10/24/2005	YP		
435	71.1	10/24/2005	YP		
435	146	10/24/2005	YP		
435	252.33	10/24/2005	YP		
536	23.2	10/24/2005	YP		
536	23.7	10/24/2005	YP		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
435	146	10/24/2005	YP	
435	252.3	10/24/2005	YPYP	
435	23.7	10/24/2005	YP	
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	DATE	EXMR
stic: seq id no:1	10/24/2005	YP
stn/east: see search history	10/24/2005	ΥP
inventor search	10/24/2005	
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